Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/762,364	MAITLAND ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

SEARCHED				
Class	Subclass	Date	Examiner	
713	150	6/23/2007	ET	
380	265, 259	6/23/2007	ET	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
INVENTOR SEARCH - PALM	6/23/2007	ET
NPL - IEEE XPLORE	6/23/2007	ET
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	6/23/2007	. ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	6/23/2007	ET